## Notice of References Cited Application/Control No. 10/537,234 Examiner Michael Bernshteyn Applicant(s)/Patent Under Reexamination KIM ET AL. Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
	В	US-			
	O	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	_	US-			
	۲	US-			
	κ	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP 05074461 A	03-1993	Japan	YOSHINO et al.	
*	0	JP 10302797 A	11-1998	Japan	NORITAKE et al.	
	Ρ	·				
	α					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	<b>V</b>					
	w					
	x	•				

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.